Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,051	YIM, MAU SHIN FRANK	
Examiner	Art Unit	

Adolf Berhane

2838

SEARCHED					
Class	Subclass	Date	Examiner		
363	37				
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307	64				
	66	3/3/2005	AB		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
307	66	3/3/2005	AB		
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